_	L#	Hits	Search Text	DBs	Time Stamp
			(Si?sub.\$3 near1 Ge?sub.\$3) (SiGe	USPAT; US-PGPUB; EPO;	2002/01/30
1	L5	3564	GeSi)	JPO; DERWENT; IBM_TDB	16:51
2 L1	1		strained adj2 (Si silicon)	USPAT; US-PGPUB; EPO;	2002/01/30
	L12	138		JPO; DERWENT; IBM_TDB	17:08
3		0	strained adj2 (Si/)	USPAT; US-PGPUB; EPO;	2002/01/30
	L19			JPO; DERWENT; IBM_TDB	
		11	strained adj2 Si/SiGe	USPAT; US-PGPUB; EPO;	2002/01/30
4	L26			JPO; DERWENT; IBM_TDB	
	1	71	5 and 12	USPAT; US-PGPUB; EPO;	2002/01/30
5	L33			JPO; DERWENT; IBM_TDB	17:12
-	<b>-</b>		33 and (thick thickness nm	USPAT; US-PGPUB; EPO;	2002/01/30
6	L40	65	nanometer ang angstrom	JPO; DERWENT; IBM_TDB	17:14
~			micrometer ".mu.m")	0,02,02	<u></u>
	<b></b>		5 same (thick thickness nm	USPAT; US-PGPUB; EPO;	2002/01/30
7	L47	1010	nanometer ang angstrom	JPO; DERWENT; IBM_TDB	17:15
•			micrometer ".mu.m")	i '	İ
	1.54	54	12 and 47	USPAT; US-PGPUB; EPO;	2002/01/30
8	L54			JPO; DERWENT; IBM_TDB	
	L61	3	5906951.pn.	USPAT; US-PGPUB; EPO;	2002/01/30
9				JPO; DERWENT; IBM_TDB	10:35
4.0	L68	77854	bond\$3 near15 (temperature degree ".degree.C")	USPAT; US-PGPUB; EPO;	2002/01/30
10	L68			JPO; DERWENT; IBM_TDB	19.17
	1.75	179	5 and 68	USPAT; US-PGPUB; EPO;	
11	L75	179	‡ ·	JPO; DERWENT; IBM_TDB	19:02
	L82	6298	68 same (nitrogen or "N.sub.2" or air or argon or Ar)	USPAT; US-PGPUB; EPO;	2002/01/30
12				JPO; DERWENT; IBM_TDE	19.10
	1.00	15	5 and 82	USPAT; US-PGPUB; EPO;	2002/01/30
13	L89			JPO; DERWENT; IBM_TDE	
14	1.00	179693	bond\$3 same (temperature degree ".degree.C")	USPAT; US-PGPUB; EPO;	2002/01/30
	L96			JPO; DERWENT; IBM_TDE	19:18
	1,400	20589	96 same (nitrogen or "N.sub.2" or air or argon or Ar)	r USPAT; US-PGPUB; EPO;	2002/01/30
15	L103			"JPO; DERVVEN I , IBIVI_ I DE	19.10
<u> </u>	T	40		USPAT; US-PGPUB; EPO;	2002/01/30
16	L110	48	5 and 103	JPO; DERWENT; IBM_TDE	3 19:19

<u> </u>	L#	Hits	Search Text	DBs	Time Stamp
	ļ <u>-</u> "			HODAT: HO DODIES EDO:	2002/04/20
1	L1	285	117/97.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
2	L8	3564	(Si?sub.\$3 near1 Ge?sub.\$3) (SiGe GeSi)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
3	L15	13210	silicon near1 germanium	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30
4	L22	14	1 and 8	USPAT; US-PGPUB; EPO;	2002/01/30
5	L29	33	1 and 15	JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO;	2002/01/30
	L36	23	29 not 8	JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO;	2002/01/30
6	-		((chemo chem chemical) near1	JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO;	<b></b>
7	L43	14438	(mech mechanical)) near2 polish\$3	JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO;	13:09
8	L50	15461	cmp	JPO; DERWENT; IBM_TDB	13:42
9	L57	21517	43 50	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30 13:43
10	L64	622	57 and (8 15)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
11	L71	129	64 and (bonded bonding)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30
12	L78	95	64 and ((bonded bonding) near15	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30
13	L85	492	(wafer substrate)) 57 same (bonded bonding)	USPAT; US-PGPUB; EPO;	2002/01/30
	L92	165	57 near20 (bonded bonding)	JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO;	2002/01/30
14	<b>-</b>			JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO;	
15	L99	153	92 and (silicon or semiconductor)	JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO;	14:15
16	L106	5	43 near20 8	JPO; DERWENT; IBM_TDB	14:42
17	L113	6861	43 near20 (si substrate wafer semiconductor silicon)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	15:19
18	L120	62	113 same (RMS or roughness)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
19	L127	17	120 and (bonded bonding)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30 14:44
20	L134	92	(si substrate wafer semiconductor silicon) same rms same bond\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30
21	L141	9	43 and 134	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30
22	L148	0	2001WO-US19613.ap,prai.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
23	L155	0	2001WO-US19613	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
24	L162	0	2001WO-US99169	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	

	L#	Hits	Search Text	DBs	Time Stamp
1	L1	3564	(Si?sub.\$3 near1 Ge?sub.\$3) (SiGe GeSi)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/01/30 11:10
2	L8	41	1 and (graded or gradient) and relaxed and bond\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
3	L15	6	1 and (stepped) and relaxed and bond\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	